Form PTO 1449 U.S. DEPAR NT OF COMMERCE (Modified) PATENT AND RADEMARK OFFICE			0057-2362-2YY		09/176,315		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT SHIGENOBU MAEDA, ET AL.			
/ %				FILED GROUP			
EXAMINER INITIAL NUMBER DATE APR 1 1 2002 EXAMINER INITIAL NUMBER Cut (AA 5,304,925 04/19/94			OCTOBER 22, 1998		2811		
/	E.	ski		S. PATENT DOCUMENTS			
EXAMINER INITIAL	100	DEMARK CUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Suil	AA	5,304,925	04/19/94	Ebina			
SWC	AB	4,257,825	03/24/81	Schaumburg		/	
	AC						_
	AD						
	AE	,					
	AF						
	AG						
	AH						
	ΑI						
	AJ						
	AK						
	AL						
	AM						
	AN						*
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY		YES	TRANSLATION NO
521	AO	05 226619	09/03/93	Japan (with English abstract)			х
	AP	61 198753	09/03/86	Japan (with English abstract)			x
	AQ	0 605812 A1	07/13/94	Europe		х	
SWC	AR	07 022601	01/24/95	Japan (with English abstract)			x
	AS						
	ΑT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY	,					
	AZ						
Examiner CRANE Date Considered 1/12/22							10/12
Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in							
conformance and not considered. Include copy of this form with next communication to applicant.							